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SIMULATION OF TRANSIENTS IN PLASMA PROCESSING REACTORS USING MODERATE PARALLELISM*

Pramod Subramonium** and Mark J. Kushner*** **Department of Chemical Engineering ***Department of Electrical and Computer Engineering University of Illinois Urbana, IL 61801

> email: subramon@uiuc.edu mjk@uiuc.edu

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- Introduction
- Description of the model
- Validation
- Properties of pulsed plasmas
 - Argon
 - Ar/Cl₂
- Conclusions

- Transient phenomena are often encountered in plasma processing
 - Pulsed operation of plasmas
 - Study startup and shutdown
 - Recipe changes
- Pulsed plasmas
 - Damage free plasma etching with better uniformity and anisotropy
 - Additional control knobs : Duty cycle and Pulse repetition frequency
 - Reduce charge buildup on wafer and suppress notching
- Difficult to resolve in multi-dimensional plasma equipment models
- Moderately parallel algorithms for hybrid models were developed to investigate the long-term transients.

- HPEM iterates modules to converged solution.
- Electromagnetics Module
 - Maxwell's equations are solved in frequency domain
- Electron-Energy Transport Module
 - Electron impact source functions and transport coefficients
 - Monte Carlo Simulation is used to generate spatially dependent EEDs
- Fluid Kinetics Module
 - Fluid transport equations for species densities, fluxes and temperature
 - Poisson's equation for time dependent electric potential
 - Ions and Neutrals : Continuity, Momentum and Energy equation
 - Electrons : Drift-diffusion equation
- Modeling truly time dependent phenomena is difficult using an modular iterative scheme

DESCRIPTION OF THE PARALLEL HYBRID MODEL

- The HPEM, a modular simulator, was parallelized by employing a shared memory programming paradigm on a Symmetric Multi-Processor (SMP) machine.
- The Electromagnetics, Electron Monte Carlo and Fluid-kinetics Modules are simultaneously executed on three processors.
- The variables which are updated in different modules are immediately made available through shared memory for use by other modules.
- Dynamic load balancing is implemented to equal the tasks on different processors.



- Parallel and serial execution gives similar results for steady state conditions in Ar plasma.
 - Electron Density
- 3-5% difference in the estimated electron density

- Electron Temperature (T_e)
- The steady state T_e is same in parallel and serial execution.



- Model results compare well with experiments*
- Simulations (1 and 2) show similar trends as in experiments
- Rates of avalanche and decay at leading edge and interpulse periods are well captured
- Quantitative agreement in column densities depends on physics model ("1" and "2")
 - "1" : Low degree of radiation trapping of Ar (4s) and Ar (4p)
 - "2" : High degree of radiation trapping of Ar (4s) and Ar (4p)
- Ar, 20 mTorr, 300 W, 10kHz/50%

* G. A. Hebner and C. B. Fleddermann, J. Appl. Phys. 82, 2814 (1997)



2-D DYNAMICS IN ARGON : ELECTRON DENSITY [e]

- The peak [e] migrates to below the coils during "power-on" where the source is maximum
- At steady state , [e] becomes more uniform.
- As the power is turned off, in the early afterglow ambipolar losses dominate over generation of electrons.
- Rate of electron decay decreases in the late afterglow.
- Faster decay of [e] in the center than at the walls due to shorter diffusion length
- Ar, 20 mTorr, 300 W, 10kHz/50%



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EFFECT OF DUTY CYCLE AND PULSE REPETITION FREQUENCY (PRF)

- EFFECT OF DUTY CYCLE
- Decay time for electron density ([e]) was longer than the off-period
- Rise time is about 25 ms
- Higher duty cycle resulted in a constant [e]



- EFFECT OF PRF
- Peak [e] is same for all cases
- Higher PRF resulted in higher time averaged [e]
- Lower PRF resulted in lower [e] in the late afterglow



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2-D DYNAMICS IN Ar/Cl₂ : CI⁻ DENSITY [CI⁻]

- When the pulse begins, the plasma potential peaks thereby "compressing" the [Cl⁻]
- At steady state, [Cl⁻] "rebounds" as the plasma potential decreases.
- Due to inertia, [CI⁻] does not respond to changes in plasma potential immediately.
- When the plasma is turned off, the [Cl⁻] increases due to a higher rate of dissociative attachment at low T_e.
- Later, the plasma potential falls and [Cl⁻] spreads.



• Ar/Cl₂ = 80/20, 20 mTorr, 300 W, 10 kHz/50%

Ar/Cl₂ : PLASMA POTENTIAL AND Cl⁻ FLUX VECTORS

- As the pulse begins, the peak plasma potential migrates to under the coils.
- As the steady state is reached, the peak plasma potential moves towards the center.
- Cl⁻ flux vectors point towards the peak plasma potential when plasma potential is large.
- It takes about 25 ms for the ions to move from periphery to the center.
- When the plasma is turned off, Cl⁻ flux vectors reverse, pointing towards boundaries.



• Ar/Cl₂ = 80/20, 20 mTorr, 300 W, 10 kHz/50%

EFFECT OF PULSE REPETITION FREQUENCY (PRF)

- Electron density (at center)
- Non-monotonic behavior in peak
 [e] is also observed in experiments.
- Lower PRF results in higher rate of dissociation due to higher T_e
- Decay rate is similar for all PRFs



- Cl⁻ density [Cl⁻] (at center)
- During plasma turn on, Cl⁻ ions move to the center
- [Cl⁻] then decreases due to ionion recombination.
- When power is removed, [CI⁻] increases and then decreases.



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EFFECT OF DUTY CYCLE ON FLUXES TO SUBSTRATE

- Flux to substrate can be controlled by varying duty cycle.
- As duty cycle increases, the flux to the substrate increases
- For 10%, plasma potential decays away in 40 ms after the turn off.
- For 50%, plasma potential decays away in 25 ms after the turn off.



- A new 2-D hybrid model was proposed to address transients based on moderate parallelism.
- Plasma transport, neutral fluid transport, and electromagnetics are simultaneously computed on separate processors.
- Computational studies were performed for pulsed operation of Ar and Ar/Cl₂ ICPs.
- In argon plasmas, the peak in electron temperature during the turn-on phase is nearly twice the steady state value.
- In electronegative plasmas, electron-ion plasma in the activeglow becomes ion-ion plasma in the afterglow.
- Negative ions do not respond immediately to plasma potential changes.
- Present study can be extended to investigate the effect of pulsed ECRs and charge buildup in fine features during etching.